

<b>Notice of References Cited</b>	Application/Control No. 10/561,369		Applicant(s)/Patent Under Reexamination SEE, RICHARD JAMES	
	Examiner Thai-Ba Trieu		Art Unit 3748	Page 1 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-889,439	06-1908	CARTER	418/195
*	B	US-1,012,616	12-1911	DUBUS	418/195
*	C	US-1,106,666	08-1914	MILLER	123/233
*	D	US-1,305,133	05-1919	LITTLE	418/195
*	E	US-2,674,982	04-1954	MCCALL WILLIAM B	123/221
*	F	US-3,277,832	10-1966	LOUIS PANIE-DUJAC MARCEL	418/195
*	G	US-3,502,054	03-1970	HAMBRIC JAMES C	123/221
*	H	US-3,726,616	04-1973	Powers, William T.	418/195
*	I	US-3,739,754	06-1973	Nutku, Ata	123/229
*	J	US-4,013,046	03-1977	Kemp, Gail W.	123/229
*	K	US-6,119,649	09-2000	Raab, Anton	123/233
*	L	US-6,276,329 B1	08-2001	Archer, John Edward	123/228
*	M	US-6,546,908 B1	04-2003	Pekau, Rudolf R.	123/206

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 9314299 A1	07-1993	World Intellect	BELANGER, J ROBERT	F01C 003/02
	O	DE 2827211 A	01-1980	Germany	NIESSEN G	F01C 003/02
	P	RU 2044893 C1	09-1995	Russian Federat	MAKUSHENKO YU M	F01C 003/02
	Q	DE 10354621 A1	06-2005	Germany	SAUER, WOLF-RUEDIGER	F01C 003/02
	R	GB 2356896 A	06-2001	United Kingdom	KHALID, MUHAMMAD YOUSUF	F01C 003/02
	S	WO 0012867 A1	03-2000	World Intellect	ONDRICH M	F01C 021/08
	T	DE 4323345 A1	01-1995	Germany	TALHOFF, WILHELM	F01C 003/02

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/561,369		Applicant(s)/Patent Under Reexamination SEE, RICHARD JAMES	
	Examiner Thai-Ba Trieu		Art Unit 3748	Page 2 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,588,395 B2	07-2003	DeFazio, Robert	123/223
*	B	US-7,059,294 B2	06-2006	Wright, Michael D.	123/233
*	C	US-3,214,907	11-1965	ERICH MARTIN	123/249
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 933500 A1	08-1999	European Patent	LINDSEY, STEPHEN FRANCIS	F01C 003/02
	O	WO 9743519 A1	11-1997	World Intellect	BOUQUET, HENRI	F01C 003/02
	P	DE 19509913 A1	09-1996	Germany	WALTER, JUERGEN	F01C 003/02
	Q	DE 4127870 A1	01-1992	Germany	LIPINSKI, JOSEF	F01C 003/02
	R	DE 4226063 A1	01-1994	Germany	BRUCH, CLAUS-DIETER	F01C 003/02
	S	JP 63227901 A	09-1988	Japan	KAGAMIYAMA, ROKUROU	F01C 003/02
	T	DE 3041606 A	06-1982	Germany	GRZANNA K	F01C 003/02

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/561,369		Applicant(s)/Patent Under Reexamination SEE, RICHARD JAMES	
	Examiner Thai-Ba Trieu		Art Unit 3748	Page 3 of 4

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

#### FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	FR 2531744 A	02-1984	France	ROUSSEAU G	F01C 003/02
	O	JP 54087911 A	07-1979	Japan	FUJISAWA et al.	F01C 003/02
	P	GB 1376908 A	12-1974	United Kingdom	UNIV NORTHWESTERN	F01C 003/02
	Q	JP 03100328 A	04-1991	Japan	MAKITA, TETSUO	F01C 003/02
	R	JP 63295818 A	12-1988	Japan	TANAKA, NOBUYUKI	F01C 003/02
	S	DE 3301726 A1	07-1984	Germany	INGELHEIM, PETER GRAF	F01C 003/08
	T	GB 2374903 A	10-2002	United Kingdom	NICCOLAI, PAOLO	F01C 001/00

#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>		Application/Control No. 10/561,369	Applicant(s)/Patent Under Reexamination SEE, RICHARD JAMES	
		Examiner Thai-Ba Trieu	Art Unit 3748	Page 4 of 4

**U.S. PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A US-			
	B US-			
	C US-			
	D US-			
	E US-			
	F US-			
	G US-			
	H US-			
	I US-			
	J US-			
	K US-			
	L US-			
	M US-			

**FOREIGN PATENT DOCUMENTS**

*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N JP 04101021 A	04-1992	Japan	ISHIWADA, HIDEO	F02B 53/00
	O SU 1830600 A1	07-1993	Soviet Union	KRASNOPEVTSEV et al.	H02K 37/00
	P WO 9635507 A1	11-1996	World Intellect	BROWN	B01F 7/02
	Q				
	R				
	S				
	T				

**NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U				
	V				
	W				
	X				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.